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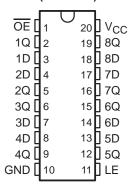
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V<sub>OLP</sub> (Output Ground Bounce) < 1 V at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C
- High-Drive Outputs (-32-mA I<sub>OH</sub>, 64-mA I<sub>OL</sub>)
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Package, and Plastic (N) and Ceramic (J) DIPs

## description

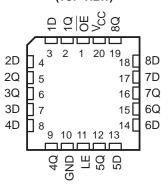
The eight latches of the 'ABT373 are transparent D-type latches. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels set up at the D inputs.

A buffered output-enable  $(\overline{OE})$  input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

SN54ABT373 . . . J OR W PACKAGE SN74ABT373 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54ABT373 . . . FK PACKAGE (TOP VIEW)



OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT373 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74ABT373 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

# FUNCTION TABLE (each latch)

	INPUTS		OUTPUT
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q <sub>0</sub>
Н	X	Χ	Z



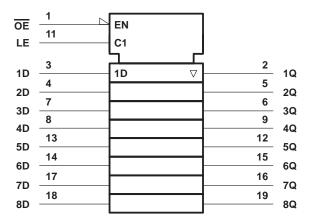
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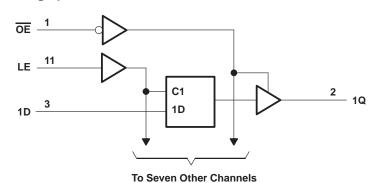
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## logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>		0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		
Voltage range applied to any output in the high	or power-off state, V <sub>O</sub>	
Current into any output in the low state, IO: SN	I54ABT373	96 mA
SN	174ABT373	
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)		–18 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)		
Package thermal impedance, θ <sub>JA</sub> (see Note 2):	: DB package	115°C/W
	DW package	97°C/W
	N package	67°C/W
	PW package	128°C/W
Storage temperature range, T <sub>stq</sub>		–65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

<sup>2.</sup> The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.



NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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#### recommended operating conditions (see Note 3)

			SN54A	BT373	SN74A	BT373	UNIT
			MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage		4.5	5.5	4.5	5.5	V
V <sub>IH</sub> High-level input voltage		2		2		V	
V <sub>IL</sub> Low-level input voltage			0.8		0.8	V	
VI	V <sub>I</sub> Input voltage		0	VCC	0	VCC	V
IOH	High-level output current			-24		-32	mA
lOL	Low-level output current			48		64	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled		5		5	ns/V
TA	Operating free-air temperature		<del>-</del> 55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED		TEST COMPLETION	10	Т	A = 25°C	;	SN54ABT373		SN74ABT373		UNIT
PARAMETER		TEST CONDITION	15	MIN	TYP <sup>†</sup>	MAX	MIN	MAX	MIN	MAX	UNII
VIK	$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA				-1.2		-1.2		-1.2	V
	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$		2.5			2.5		2.5		
Varia	V <sub>CC</sub> = 5 V,	$I_{OH} = -3 \text{ mA}$		3			3		3		V
VOH	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = -24 mA		2			2				V
	VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$		2*					2		
Vai	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 48 mA				0.55		0.55			V
VOL	vCC = 4.5 v	I <sub>OL</sub> = 64 mA				0.55*				0.55	V
V <sub>hys</sub>					100						mV
lį	$V_{CC} = 5.5 \text{ V},$	$V_I = V_{CC}$ or GND				±1		±1		±1	μΑ
lozh	$V_{CC} = 5.5 V$ ,	$V_0 = 2.7 \text{ V}$				10 <sup>‡</sup>		10‡		10‡	μΑ
lozL	$V_{CC} = 5.5 V$ ,	V <sub>O</sub> = 0.5 V				-10 <sup>‡</sup>		-10 <sup>‡</sup>		-10‡	μΑ
l <sub>off</sub>	$V_{CC} = 0$ ,	$V_I$ or $V_O \le 4.5 \text{ V}$				±100				±100	μΑ
ICEX	$V_{CC} = 5.5 V,$	V <sub>O</sub> = 5.5 V	Outputs high			50		50		50	μΑ
ΙΟ§	$V_{CC} = 5.5 V,$	V <sub>O</sub> = 2.5 V		-50	-100	-180	-50	-180	-50	-180	mA
			Outputs high		1	250		250		250	μΑ
ICC	$V_{CC} = 5.5 \text{ V}, \text{ I}_{C}$ $V_{I} = V_{CC} \text{ or } G$	ND ) = 0,	Outputs low		24	30		30		30	mA
	1, 100 81 81		Outputs disabled		0.5	250		250		250	μΑ
∆I <sub>CC</sub> ¶	V <sub>CC</sub> = 5.5 V, C Other inputs at	One input at 3.4 V, VCC or GND				1.5		1.5		1.5	mA
Ci	V <sub>I</sub> = 2.5 V or 0.	.5 V			3						pF
Co	$V_0 = 2.5 \text{ V or } 0$	0.5 V			6						pF

<sup>\*</sup> On products compliant to MIL-PRF-38535, this parameter does not apply.



<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ .

<sup>&</sup>lt;sup>‡</sup>This data sheet limit may vary among suppliers.

Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

					SN54ABT373			
		V <sub>CC</sub> =	CC = 5 V, A = 25°C MIN MA		MAX	UNIT		
			MIN	MAX				
t <sub>W</sub> Pulse duration, LE high			3.3		3.3		ns	
t.	A		High	2.2		2.5		ns
t <sub>Su</sub> Setup t	Setup time, data before LE↓	etup time, data before LE↓		2.2		2.5		115
th	Hold time, data after LE↓		High or low	2.2		2.5		ns

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

				SN74ABT373				
		V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C		MIN	MAX	UNIT		
			MIN	MAX				
t <sub>W</sub>	t <sub>W</sub> Pulse duration, LE high			3.3		3.3		ns
			High	1.9	9 1.9			
t <sub>su</sub> Setup	Setup time, data before LE↓	etup time, data before LE↓	Low	1.5		1.5		ns
t <sub>h</sub>	Hold time, data after LE↓	_	High or low	1	·	1		ns

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L$  = 50 pF (unless otherwise noted) (see Figure 1)

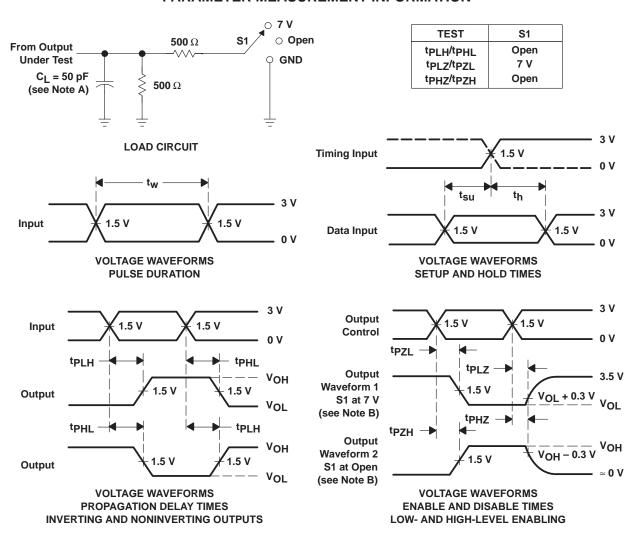
			SN54ABT373						
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C		TO $V_{CC} = 5 \text{ V},$ (OUTPUT) $T_A = 25^{\circ}\text{C}$ MIN	V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C MIN MA		MAX	UNIT
			MIN	TYP	MAX				
t <sub>PLH</sub>	D	Q	1.9	3.9	5.4	1.3	6.8	ns	
t <sub>PHL</sub>		Q	2.2	4.2	5.7	2	7	115	
t <sub>PLH</sub>	LE	Q	2.2	4.6	6.1	1.8	7.7	ne	
<sup>t</sup> PHL		Q	3.2	5.2	6.7	2.5	7.7	ns	
<sup>t</sup> PZH	ŌĒ	Q	1.2	3.2	5.5	1	6.2	ns	
<sup>t</sup> PZL	OE	Q	2	4.7	6.2	1.5	7.2	115	
<sup>t</sup> PHZ	ŌĒ		2.5	4.9	6.4	2.4	8	nc	
t <sub>PLZ</sub>	OE	Q	2	4.5	6	2	7	ns	

switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L = 50$  pF (unless otherwise noted) (see Figure 1)

				SN	74ABT3	73			
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C			MIN	MAX	UNIT	
			MIN	TYP	MAX				
<sup>t</sup> PLH	D	Q	1.9	3.9	5.4	1.9	5.9	ne	
<sup>t</sup> PHL		ų ,	2.2	4.2	5.7	2.2	6.2	ns	
<sup>t</sup> PLH	LE	Q	2.2	4.6	6.1	2.2	6.6	ne	
<sup>t</sup> PHL	LE	ų ,	3.2	5.2	6.7	3.2	7.2	ns	
<sup>t</sup> PZH	ŌĒ	Q	1.2	3.2	4.7	1.2	5.2	ns	
<sup>t</sup> PZL	OE	ų ,	2.7	4.7	6.2	2.7	6.7	115	
<sup>t</sup> PHZ	<del></del>	Q	2.5	4.9	6.4	2.5	6.9	ne	
t <sub>PLZ</sub>	ŌĒ		2	4.5	6	2	6.5	ns	

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#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_{Q} = 50~\Omega$ ,  $t_{\Gamma} \leq$  2.5 ns,  $t_{\Gamma} \leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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